



# Human Exposure Report

**Application No.:** SZEM1911020748CR  
**Applicant:** ASAP Technology(Jiangxi) Co., Ltd.  
**Address of Applicant:** Ji'an Industrial Park, Ji'an, Jiangxi 343100 China  
**Manufacturer:** ASAP Technology(Jiangxi) Co., Ltd.  
**Address of Manufacturer:** Ji'an Industrial Park, Ji'an, Jiangxi 343100 China  
**Factory:** LUXSHARE-ICT (VIETNAM) LIMITED  
**Address of Factory:** E Lot, Quang Chau Industrial zone, Quang Chau Commune, Viet Yen district, Bac Giang Province, Vietnam

**Equipment Under Test (EUT):**

**EUT Name:** UNIV WIRELESS VENT MOUNT  
**Model No.:** LACC077, WIABLK100008847 ♣

♣ Please refer to section 2 of this report which indicates which model was actually tested and which were electrically identical.

**FCC ID:** 2APXNLACC077  
**Standard(s) :** 47 CFR PART 1, Subpart I, Section 1.1310  
**Date of Receipt:** 2019-11-29  
**Date of Test:** 2019-12-13 to 2020-02-24  
**Date of Issue:** 2020-02-24

<b>Test Result:</b>	<b>Pass*</b>
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\* In the configuration tested, the EUT complied with the standards specified above

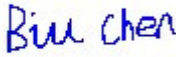

Keny Xu  
 EMC Laboratory Manager



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<b>Revision Record</b>				
<b>Version</b>	<b>Chapter</b>	<b>Date</b>	<b>Modifier</b>	<b>Remark</b>
01		2020-02-24		Original

<b>Authorized for issue by:</b>			
			
		<hr/> <b>Bill Chen /Project Engineer</b>	
			
		<hr/> <b>Eric Fu /Reviewer</b>	



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## 2 General Information

### 2.1 Details of E.U.T.

Power supply:	Input:DC 5V-12V 1.5A Max Wireless Output:10W Max
Cable:	Car cable:90cm unshielded
Antenna Type:	Loop Antenna
Antenna Gain:	0dBi
Modulation Type:	Load Modulation
Operation Frequency:	126.122KHz to 128.686kHz
Remark:	This device has been tested the worst status of full load and the device has been tested with load at 5W,7.5W and 10W, the worst case 10W is reported only.

### 2.2 Description of Support Units

Description	Manufacturer	Model No.	Serial No.
iPhone 8	Apple	A1863	F4GVQ656JC6D
SAMSUNG Galaxy S8	SAMSUNG	SM-G9500	R28J9140LPB
Rechargeable Battery	Gadlee	DP00027	REF. No.SEA2800

**Remark:**

Model No.: LACC077, WIABLK100008847

Only the model WIABLK100008874 was tested, since the electrical circuit design, layout, components used, internal wiring and functions were identical for all the above models, with only difference on model No. and the appearance.



## 2.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen Branch E&E Lab,

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China 518057.

Tel: +86 755 2601 2053 Fax: +86 755 2671 0594

No tests were sub-contracted.

## 2.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **A2LA (Certificate No. 3816.01)**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation (A2LA). Certificate No. 3816.01.

- **VCCI**

The 3m Fully-anechoic chamber for above 1GHz, 10m Semi-anechoic chamber for below 1GHz, Shielded Room for Mains Port Conducted Interference Measurement and Telecommunication Port Conducted Interference Measurement of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-20026, R-14188, C-12383 and T-11153 respectively.

- **FCC –Designation Number: CN1178**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

- **Innovation, Science and Economic Development Canada**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized by ISED as an accredited testing laboratory.

CAB identifier: CN0006.

IC#: 4620C.

## 2.5 Deviation from Standards

None.

## 2.6 Abnormalities from Standard Conditions

None.



### 3 Equipments Used during Test

Item	Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. Due date
1	3m Semi-Anechoic Chamber	ETS-LINDGREN	N/A	SEL0017	2020-06-10
2	Electric and Magnetic Field Analyzer	Narda	EHP-50F	EMC092	2020-05-06



## 4 Test Results

### 4.1 RF Exposure test

Test Requirement: 47 CFR PART 1, Subpart I, Section 1.1310  
Measurement Distance: 0/2/4/6/8/10/15cm  
Limit:

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm <sup>2</sup> )	Averaging time (minutes)
<b>(A) Limits for Occupational/Controlled Exposures</b>				
0.3-3.0	614	1.63	*(100)	6
3.0-30	1842/f	4.89/f	*(900/f <sup>2</sup> )	6
30-300	61.4	0.163	1.0	6
300-1500	/	/	f/300	6
1500-100,000	/	/	5	6
<b>(B) Limits for General Population/Uncontrolled Exposure</b>				
0.3-1.34	614	1.63	*(100)	30
1.34-30	824/f	2.19/f	*(180/f <sup>2</sup> )	30
30-300	27.5	0.073	0.2	30
300-1500	/	/	f/1500	30
1500-100,000	/	/	1.0	30

F=frequency in MHz

\*=Plane-wave equivalent power density

RF exposure compliance will need to be determined with respect to 1.1307(c) and (d) of the FCC rules. The emissions should be within the limits at 300kHz in Table 1 of 1.1310(use the 300kHz limits for 150kHz:614V/m,1.63A/m).

#### 4.1.1 E.U.T. Operation

Operating Environment:

Temperature: 24.0 °C Humidity: 52 % RH Atmospheric Pressure: 1015 mbar

EUT Operation:

This device has been tested the worst status of full load and the device has been tested with mobile phone at zero charge, intermediate charge, and full charge.



**4.1.2 Measurement Data**

**Output Voltage=DC 12V; The max output power =10W**

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	0	Side 1	0.3522	0.815
		Side 2	0.1768	0.815
		Side 3	0.3439	0.815
		Side 4	0.2273	0.815
		Top	0.2638	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	2	Side 1	0.2994	0.815
		Side 2	0.1503	0.815
		Side 3	0.2923	0.815
		Side 4	0.1939	0.815
		Top	0.2242	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	4	Side 1	0.2634	0.815
		Side 2	0.1322	0.815
		Side 3	0.2572	0.815
		Side 4	0.1706	0.815
		Top	0.1973	0.815





**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	6	Side 1	0.2266	0.815
		Side 2	0.1137	0.815
		Side 3	0.2212	0.815
		Side 4	0.1462	0.815
		Top	0.1697	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	8	Side 1	0.1858	0.815
		Side 2	0.0933	0.815
		Side 3	0.1814	0.815
		Side 4	0.1199	0.815
		Top	0.1272	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	10	Side 1	0.1486	0.815
		Side 2	0.0746	0.815
		Side 3	0.1451	0.815
		Side 4	0.0959	0.815
		Top	0.1113	0.815



**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result (A/m)	50% Limit (A/m)
127 kHz	15	Side 1	0.0834	0.815
		Side 2	0.0419	0.815
		Side 3	0.0814	0.815
		Side 4	0.0538	0.815
		Top	0.0625	0.815

**Mobile phone has been charge at zero charge, intermediate charge, and full charge.**

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	0	Side 1	0.3618	0.3459	0.3417	0.815
		Side 2	0.1868	0.1722	0.1687	0.815
		Side 3	0.3532	0.3373	0.3333	0.815
		Side 4	0.2380	0.2258	0.2212	0.815
		Top	0.2759	0.2602	0.2558	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	2	Side 1	0.3135	0.2996	0.2959	0.815
		Side 2	0.1622	0.1469	0.1419	0.815
		Side 3	0.3049	0.2904	0.2860	0.815
		Side 4	0.2048	0.1917	0.1866	0.815
		Top	0.2357	0.2246	0.2206	0.815



**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	4	Side 1	0.2759	0.2605	0.2555	0.815
		Side 2	0.1412	0.1305	0.1257	0.815
		Side 3	0.2682	0.2527	0.2481	0.815
		Side 4	0.1831	0.1676	0.1634	0.815
		Top	0.2088	0.1955	0.1917	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	6	Side 1	0.2379	0.2221	0.2175	0.815
		Side 2	0.1228	0.1120	0.1086	0.815
		Side 3	0.2327	0.2177	0.2128	0.815
		Side 4	0.1554	0.1443	0.1407	0.815
		Top	0.1805	0.1695	0.1646	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	8	Side 1	0.1963	0.1821	0.1754	0.815
		Side 2	0.1041	0.0897	0.0859	0.815
		Side 3	0.1927	0.1813	0.1778	0.815
		Side 4	0.1288	0.1141	0.1092	0.815
		Top	0.1482	0.1357	0.1310	0.815



**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	10	Side 1	0.1612	0.1477	0.1432	0.815
		Side 2	0.0865	0.0738	0.0697	0.815
		Side 3	0.1544	0.1278	0.1364	0.815
		Side 4	0.1064	0.0961	0.0912	0.815
		Top	0.1210	0.1056	0.1019	0.815

**Magnetic Field Emissions**

Operation frequency	Test Distance (cm)	Test Position	Probe Measure Result(A/m)			50%Limit (A/m)
			10% charge	50% charge	90% charge	
127 kHz	15	Side 1	0.0955	0.0824	0.0785	0.815
		Side 2	0.0533	0.0431	0.0393	0.815
		Side 3	0.0914	0.0797	0.0759	0.815
		Side 4	0.0631	0.0524	0.0488	0.815
		Top	0.0736	0.0615	0.0567	0.815

- End of the Report -

